

touch, test, invent®

...With the next generation current and voltage source/measure instruments from Keithley!

The advantage of a touchscreen interface lies in helping you get to your test results quickly and with the high degree of accuracy you'd expect from a Keithley source/measure instrument. These touchscreen instruments enable:

- Intuitive user interface minimizes your learning curve
- Easy navigation between setup and configuration menus means fewer errors
- Real time graphing & data visualization get you to your answer faster

Touchscreen Source Measure Units



	General Purpose (Up to 1A)	High Current (>1A)
Model	2450	2460
Current Range	10fA – 1A	1pA – 7A
Voltage Range	10nV – 200V	100nV – 100V
Power	20W	100W
Price	\$5,400	\$7,500

Get more info on the [Model 2450](#) and [Model 2460](#) touchscreen SMUs.

Non-Touchscreen Source Measure Units



	General Purpose (Up to 1A)				High Current (>1A)			
Model	2400	2401	2410	6430	2420	2425	2430	2440
Current Range	Up to 1A			As low as 10aA	up to 5A DC, 10A Pulse (2430)			
Voltage Range	Up to 1 kV			1μV – 200V	1uV – 100V			
Power	20W			2W	60W	100W	1000W Pulse	50W
Price	\$4,720	\$3,470	\$6,750	\$14,300	\$6,760	\$8,050	\$11,800	\$7,690

For System Level Testing Use IVy And Continue the Touchscreen Journey with 2600B SourceMeter Units



For system level, Keithley offers faster instruments for source-measure purposes, especially if you're looking for:

- 10A Pulse and high speed production test capabilities
- Single and Dual channel models for 2 and three terminal device applications
- Real-time instrument control with the versatile [IVy](#)*

*IVy is an Android App available for free on Google Play

Any of the [2600B System Source Measure Units](#) can run high speed, embedded test scripts with Test Script Processor technology providing 10x the throughput over PC/GPIB control, leading to a complete measurement and automation solution.

	Single Channel				Dual Channel				
Model	2601B	2611B	2635B	2602B	2604B	2612B	2614B	2634B	2636B
Power	40W/30W		30W	40W/channel		30W/channel		30W/channel	
Current Range	Up to 3A DC		0.1fA – 1.5A DC	Up to 3A DC		100fA – 1.5A DC		0.1fA – 1.5A DC	
Voltage Range	Up to 200V		100nV-200V	100nV-40V		100nV-200V		100nV-200V	
Price	\$6,650	\$9,910	\$9,760	\$8,090	\$9,760	\$8,090	\$12,700	\$15,300	

Interested in High Power Semiconductor Characterization?

For high – power electronics and materials, and to make measurements such as:

- On-state current
- Breakdown voltage
- Pulse measurements

Also, enable real time characterization and analysis using our ACS software with the Parametric Curve Tracers.



	Sourcemeter		Parametric Curve Tracer			
	Low Power	High Power	Low Power	High Current	High Voltage	High I and V
Model	2657A	2651A	2600-PCT-1B	2600-PCT-2B	2600-PCT-3B	2600-PCT-4B
Max. Current	120mA	50A	10A	50A	10A	50A
Max. Voltage	3kV	40V	200V	200V	3kV	3kV
Power	180W	2000W pulse	2kW	2kW	3.6kW	3.6kW
Price	\$20,200	\$16,200	Call For Price	Call For Price	Call For Price	Call For Price

Looking for a High-Performance Lab or Production System?

Source Measure Unit technology serves as the basis for our Semiconductor Parametric Analyzer and Test Systems.

An All-In-One Characterization Analyzer: [Model 4200-SCS](#)

For electrical characterization of materials, semiconductor devices and processes consider the 4200-SCS, a fully integrated analyzer. Use it to perform C-V or I-V measurements, including ultra-fast pulsed and transient I-V.

Semiconductor Wafer/Device Test: [S530](#) and [S500](#) Systems:

In production or the lab, [S530 Parametric Test Systems](#) can be flexibly applied across many devices, making it easy to adapt it for varying test plan, automation, data management, and probe station requirements.

For semiconductor characterization at the device, wafer, or cassette level, [S500 Integrated Test Systems](#) offer special capabilities such as pulse generation and ultra-fast IV for memory characterization, charge pumping, and powerful and flexible ACS software. High-voltage, current and power source measure units are part of the instrumentation.

